

**Notice of References Cited**Application/Control No.  
**09/540,201**Applicant(s)/Patent Under Reexam  
**Bitsche et al.**Examiner  
**Thanh Lam**Art Unit  
**2834**

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	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
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	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Country	Name	Classification <sup>2</sup>	
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**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
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